Application/Control No. Applicant(s)/Patent Under Reexamination 10/644,604 WALSH ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 **Anthony Weier** 1761 U.S. PATENT DOCUMENTS **Document Number** Date Country Code-Number-Kind Code Name Classification MM-YYYY * US-5,300,312 04-1994 Lusas et al. 426/634 * US-4,338,340 07-1982 426/104 В Morimoto et al. * US-3,886,299 05-1975 Feldbrugge et al. С 426/656 US-5,366,748 11-1994 D Villagran et al. 426/549 US-Ε US-F US-G US-Н US-J US-US-Κ US-L US-M FOREIGN PATENT DOCUMENTS **Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY JP 58-28235 02-1983 N, Japan 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

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